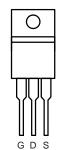


AP15N03P-VB Datasheet N-Channel 30-V (D-S) MOSFET

PRODUCT SUMMARY	
V _{DS} (V)	30
$R_{DS(on)}$ (Ω) at V_{GS} = 10 V	0. 006
$R_{DS(on)}$ (Ω) at V_{GS} = 4.5 V	0. 009
I _D (A)	80
Configuration	Single
Package	TO-220AB

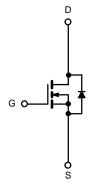
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FEATURES

- Trench Power MOSFET
- 100 % R_g and UIS Tested
- Compliant to RoHS Directive 2011/65/EU





N-Channel MOSFET

ABSOLUTE MAXIMUM RATING	S (T _A = 25 °C, unle	ess otherwise n	oted)	
Parameter		Symbol	Limit	Unit
Drain-Source Voltage		V _{DS}	30	V
Gate-Source Voltage		V _{GS}	± 20	v
	T _C = 25 °C		80	
Continuous Drain Current (T - 175 °C)	T _C = 70 °C		65	
Continuous Drain Current (T _J = 175 °C)	T _A = 25 °C	I _D	25.8 ^{b, c}	Α
	T _A = 70 °C		20 ^{b, c}	
Pulsed Drain Current	·	I _{DM}	200	
Avalanche Current Pulse	L = 0.1 mH	I _{AS}	39	
Single Pulse Avalanche Energy		E _{AS}	94.8	mJ
Continuous Source-Drain Diode Current	T _C = 25 °C	la la	50 ^{a, e}	A
Continuous Source-Drain Diode Current	T _A = 25 °C	I _S	3.13 ^{b, c}	
	T _C = 25 °C		120 ^a	
Movimum Dower Dissinction	T _C = 70 °C	D_	85	w
Maximum Power Dissipation	T _A = 25 °C	P _D –	3.75 ^{b, c}	vv
	T _A = 70 °C		2.63 ^{b, c}	
Operating Junction and Storage Temperature R	ange	T _J , T _{stg}	- 55 to 175	°C

THERMAL RESISTANCE RATING	S				
Parameter		Symbol	Тур.	Max.	Unit
Maximum Junction-to-Ambient ^{b, d}	$t \le 10 \text{ sec}$	R _{thJA}	32	40	°C/W
Maximum Junction-to-Case	Steady State	R _{thJC}	0.5	0.6	C/VV

Notes: a. Based on T_C = 25 °C. b. Surface mounted on 1" x 1" FR4 board. c. t = 10 sec. d. Maximum under steady state conditions is 90 °C/W. e. Calculated based on maximum junction temperature. Package limitation current is 90 A.

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V	/ww.\	/Bsemi.com

Parameter	Symbol	Test Conditions	Min.	Тур.	Max.	Unit
Static					1	
Drain-Source Breakdown Voltage	V _{DS}	$V_{GS} = 0 V, I_{D} = 250 \mu A$	30			V
V _{DS} Temperature Coefficient	$\Delta V_{DS}/T_{J}$	1 250 4		35		
V _{GS(th)} Temperature Coefficient	$\Delta V_{GS(th)}/T_J$	I _D = 250 μA		- 7.5		mV/°C
Gate-Source Threshold Voltage	V _{GS(th)}	$V_{DS} = V_{GS}, I_{D} = 250 \ \mu A$	1.0		2.5	V
Gate-Source Leakage	I _{GSS}	$V_{DS} = 0 V, V_{GS} = \pm 20 V$			± 100	nA
		$V_{DS} = 30 \text{ V}, \text{ V}_{GS} = 0 \text{ V}$			1	
Zero Gate Voltage Drain Current	I _{DSS}	$V_{DS} = 30 \text{ V}, \text{ V}_{GS} = 0 \text{ V}, \text{ T}_{J} = 55 ^{\circ}\text{C}$			10	μA
On-State Drain Current ^a	I _{D(on)}	$V_{DS} \ge 5 \text{ V}, V_{GS} = 10 \text{ V}$	90			Α
Drain-Source On-State Resistance ^a		V _{GS} = 10 V, I _D = 28.8 A		0.006		
	R _{DS(on)}	V _{GS} = 4.5 V, I _D = 30 A		0.009		Ω
Forward Transconductance ^a	9 _{fs}	V _{DS} = 15 V, I _D = 28.8 A		160		S
Dynamic ^b	I					1
Input Capacitance	C _{iss}			1600		
Output Capacitance	C _{oss}	$V_{DS} = 15 \text{ V}, V_{GS} = 0 \text{ V}, f = 1 \text{ MHz}$		525		pF
Reverse Transfer Capacitance	C _{rss}			370		
T () 0 ()		V_{DS} = 15 V, V_{GS} = 10 V, I_{D} = 28.8 A		35	45	
Total Gate Charge	Qg			25	35	
Gate-Source Charge	Q _{gs}	V_{DS} = 15 V, V_{GS} = 4.5 V, I_{D} = 28.8 A		15		nC
Gate-Drain Charge	Q _{gd}			20		
Gate Resistance	R _g	f = 1 MHz		1.4	2.1	Ω
Turn-On Delay Time	t _{d(on)}			18	27	
Rise Time	t _r	V_{DD} = 15 V, R _L = 0.625 Ω		11	17	
Turn-Off Delay Time	t _{d(off)}	$I_D \cong$ 24 A, V_{GEN} = 10 V, R_g = 1 Ω		70	105	
Fall Time	t _f			10	15	
Turn-On Delay Time	t _{d(on)}			55	83	ns
Rise Time	t _r	V_{DD} = 15 V, R_L = 0.67 Ω		180	270	-
Turn-Off Delay Time	t _{d(off)}	$\rm I_D\cong$ 22.5 A, $\rm V_{GEN}$ = 4.5 V, $\rm R_g$ = 1 Ω		55	83	
Fall Time	t _f			12	18	
Drain-Source Body Diode Characteristic	s					1
Continuous Source-Drain Diode Current	۱ _S	T _C = 25 °C			120	^
Pulse Diode Forward Current ^a	I _{SM}				120	A
Body Diode Voltage	V _{SD}	I _S = 22 A		0.8	1.2	V
Body Diode Reverse Recovery Time	t _{rr}			52	78	ns
Body Diode Reverse Recovery Charge	Q _{rr}			70.2	105	nC
Reverse Recovery Fall Time	t _a	$I_F = 20 \text{ A}, \text{ di/dt} = 100 \text{ A/}\mu\text{s}, T_J = 25 \text{ °C}$		27		
Reverse Recovery Rise Time	t _b			25	1	ns

Notes:

a. Pulse test; pulse width \leq 300 $\mu s,$ duty cycle \leq 2 %.

b. Guaranteed by design, not subject to production testing.

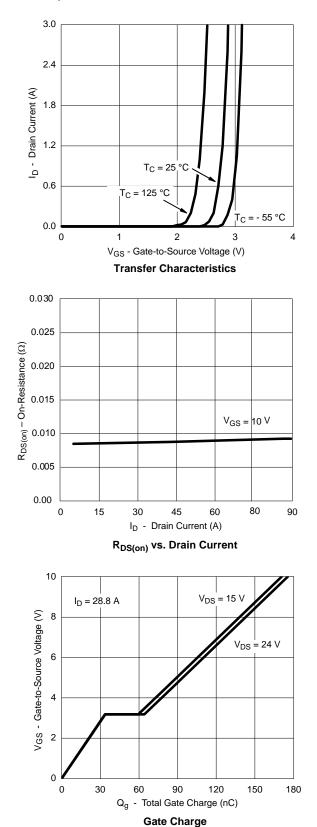
Stresses beyond those listed under "Absolute Maximum Ratings" may cause permanent damage to the device. These are stress ratings only, and functional operation of the device at these or any other conditions beyond those indicated in the operational sections of the specifications is not implied. Exposure to absolute maximum rating conditions for extended periods may affect device reliability.



90 V_{GS} = 10 V thru 4 V 75 60 I_D - Drain Current (A) 45 30 15 $V_{IGS} = 2 V$ $V_{GS} = 3 V$ 0 2.0 2.5 0.0 0.5 1.0 1.5 V_{DS} - Drain-to-Source Voltage (V) **Output Characteristics** 600 T_C = 25 °C 500 G_{fs} - Transconductance (S) T_C = 125 °C 400 300 T_C = - 55 °C 200 100 0 0 10 20 30 70 80 90 40 50 60 I_D - Drain Current (A) Transconductance 2500 Ciss 2000 C - Capacitance (pF) 1500 1000 Coss 500 Crss 0 0 6 12 18 24 30 V_{DS} - Drain-to-Source Voltage (V)

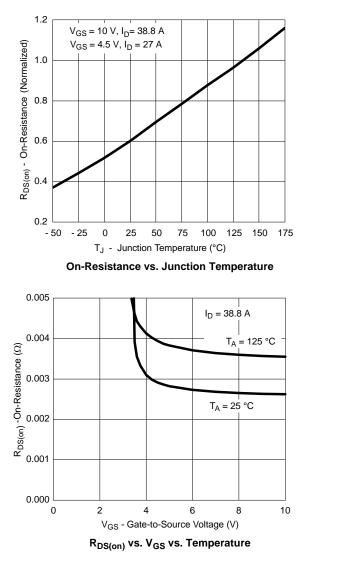
TYPICAL CHARACTERISTICS (25 °C, unless otherwise noted)

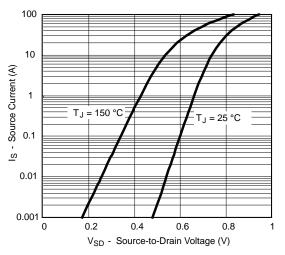
Capacitance



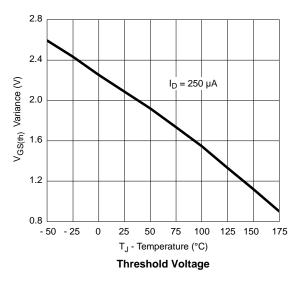


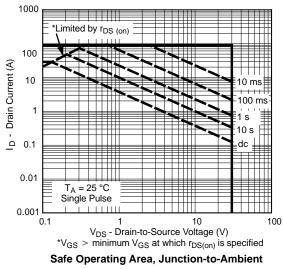




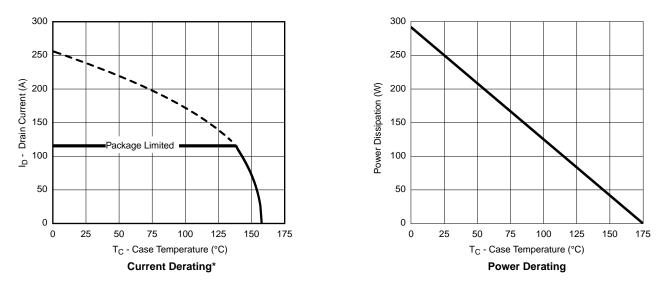


Forward Diode Voltage vs. Temperature



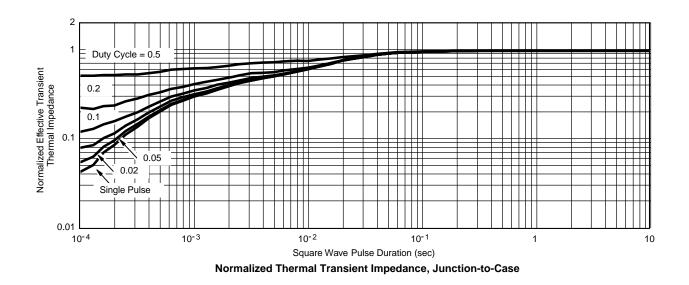






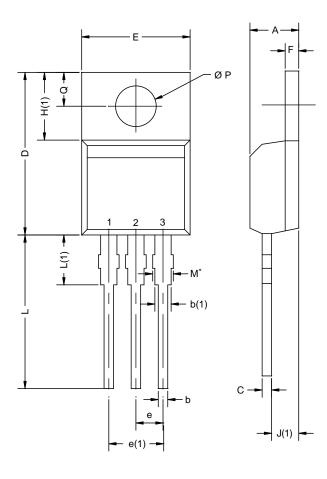
TYPICAL CHARACTERISTICS (25 °C, unless otherwise noted)

*The power dissipation P_D is based on $T_{J(max)} = 175$ °C, using junction-to-case thermal resistance, and is more useful in settling the upper dissipation limit for cases where additional heatsinking is used. It is used to determine the current rating, when this rating falls below the package limit.





TO-220AB



	MILLIN	IETERS	INCHES		
DIM.	MIN.	MAX.	MIN.	MAX.	
А	4.25	4.65	0.167	0.183	
b	0.69	1.01	0.027	0.040	
b(1)	1.20	1.73	0.047	0.068	
С	0.36	0.61	0.014	0.024	
D	14.85	15.49	0.585	0.610	
Е	10.04	10.51	0.395	0.414	
е	2.41	2.67	0.095	0.105	
e(1)	4.88	5.28	0.192	0.208	
F	1.14	1.40	0.045	0.055	
H(1)	6.09	6.48	0.240	0.255	
J(1)	2.41	2.92	0.095	0.115	
L	13.35	14.02	0.526	0.552	
L(1)	3.32	3.82	0.131	0.150	
ØΡ	3.54	3.94	0.139	0.155	
Q	2.60	3.00	0.102	0.118	
ECN: X12- DWG: 547	0208-Rev. N, 1	08-Oct-12			

Notes

 * M = 1.32 mm to 1.62 mm (dimension including protrusion) Heatsink hole for HVM



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